



**INTERNATIONAL  
RELIABILITY PHYSICS SYMPOSIUM**

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**2002 TUTORIAL NOTES  
Reliability Fundamentals**

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- Topic 112. CHARACTERIZATION, PHYSICAL MODELING AND ASSESSMENT OF GATE OXIDE RELIABILITY  
*Eric Vogel, NIST*
- Topic 113. ESD BASICS  
*Charvaka Duvvury, Texas Instruments*
- Topic 121. RADIATION INDUCED SOFT ERRORS IN SILICON COMPONENTS & COMPUTER SYSTEMS  
*Organized by Robert Baumann, Texas Instruments & Jose Maiz, Intel*
- Topic 131. ERRORS AND RELIABILITY  
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*Ennis Ogawa, Texas Instruments*
- Topic 142. INTRODUCTION TO PREDICTIVE WAFER LEVEL RELIABILITY  
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# RELIABILITY FUNDAMENTALS

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*Organized by Robert Baumann, Texas Instruments & Jose Maiz, Intel*
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*Norbert Seifert, Compact Computers*
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*Mike Tucker, Alpha Sciences Inc.*
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